

PATENT  
2390-1-001IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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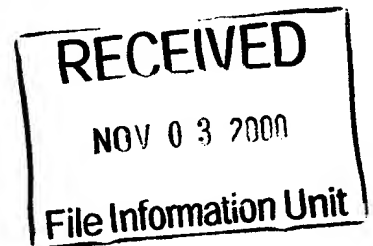
SERIAL NO. : 09/254,521

FILED : March 8, 1999

FOR : APPARATUS AND METHOD FOR DETECTING MICRO  
DEFECTS IN SEMI-CONDUCTORS

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Sir:

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